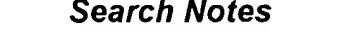


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	09/661,806	HASEGAWA ET AL.
	<b>Examiner</b>	Art Unit
	Sunray Chang	2121

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
703	2	8/7/2005	SC
345	419-441	8/7/2005	SC